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EECS251B : Advanced Digital Circuits and Systems



Lecture 14 – Latches

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AMD Allies with Ranovus on Data Center Photonics Module
March 6, 2022, EETimes

The co-packaged optical (CPO) demonstration system built by Xilinx and Ranovus. It incorporates the former's Versal ACAP with the latter's Odin Analog-Drive CPO 2.0. (Source: Ranovus)



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Recap

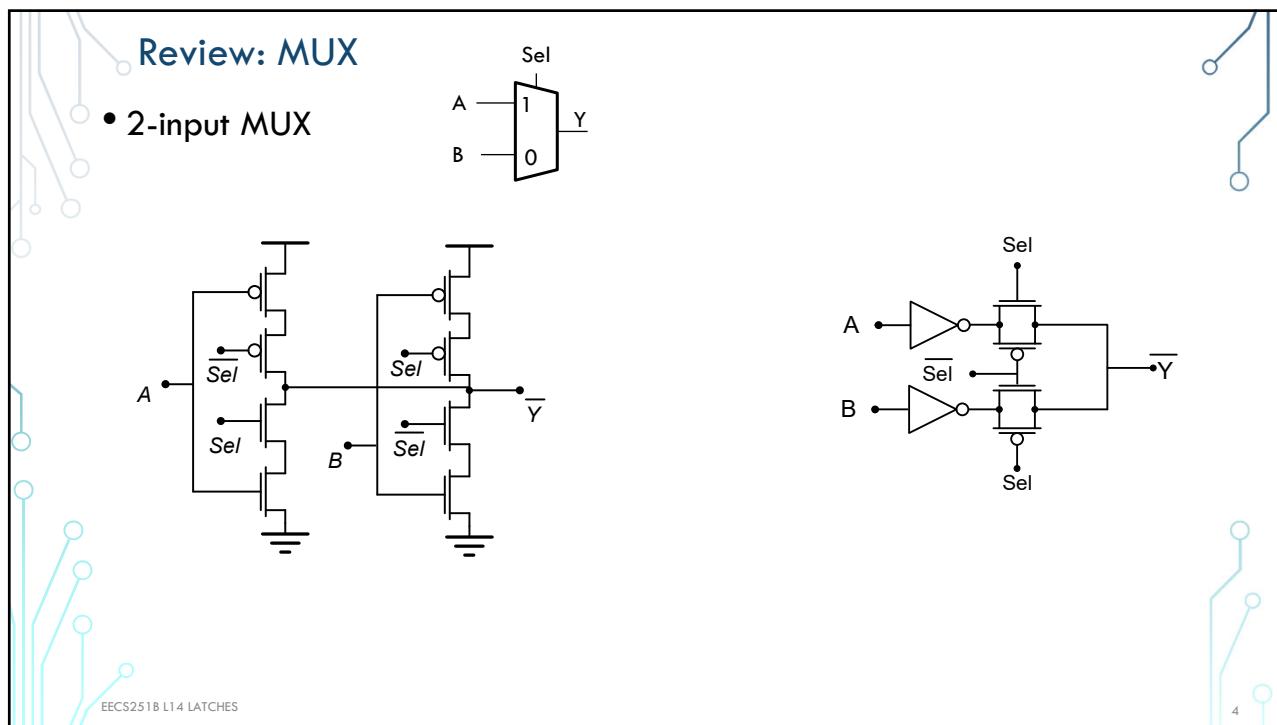
- Flip-flop-based (edge-triggered) timing dominates today
- Latch-based timing can increase performance, but needs extra care
- There is also asynchronous design

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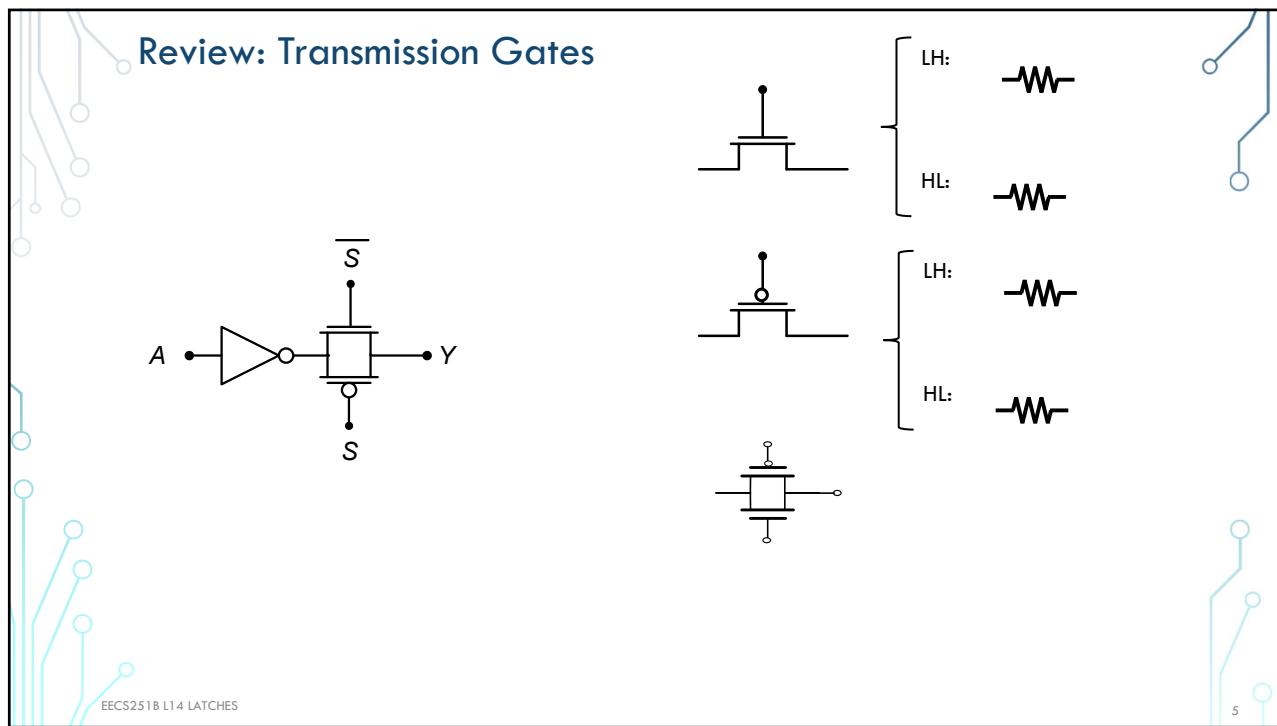
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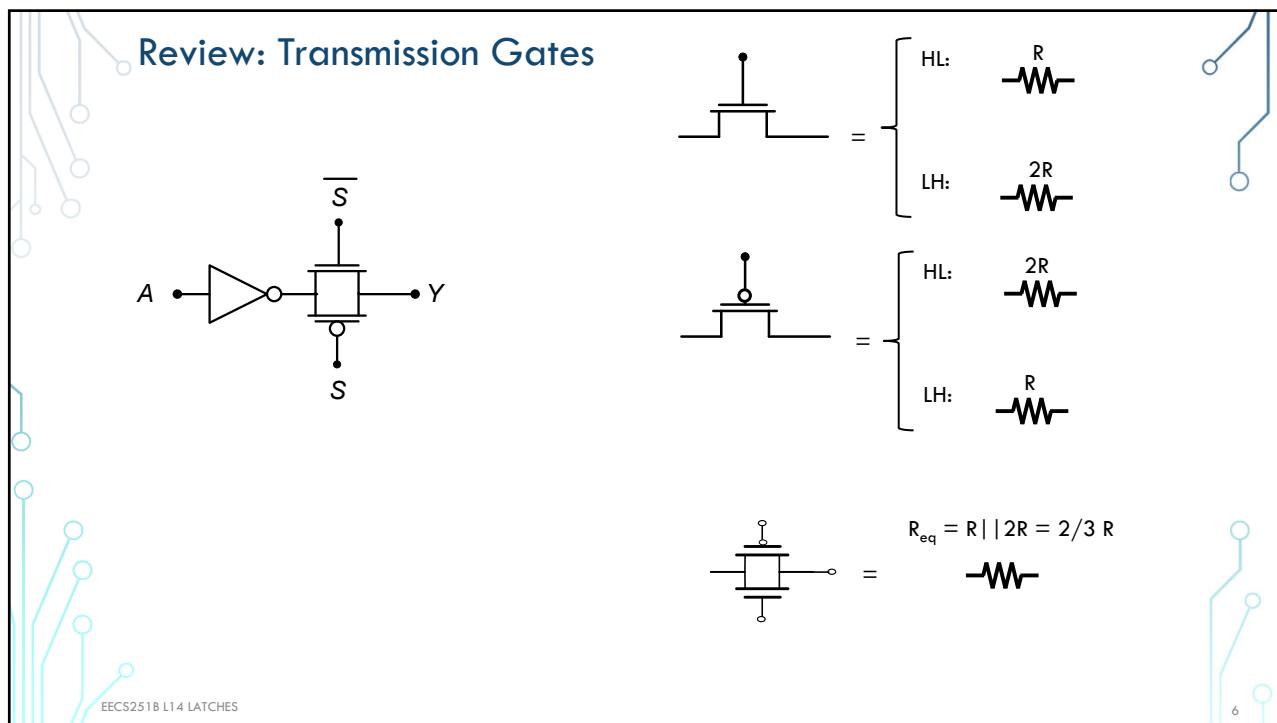
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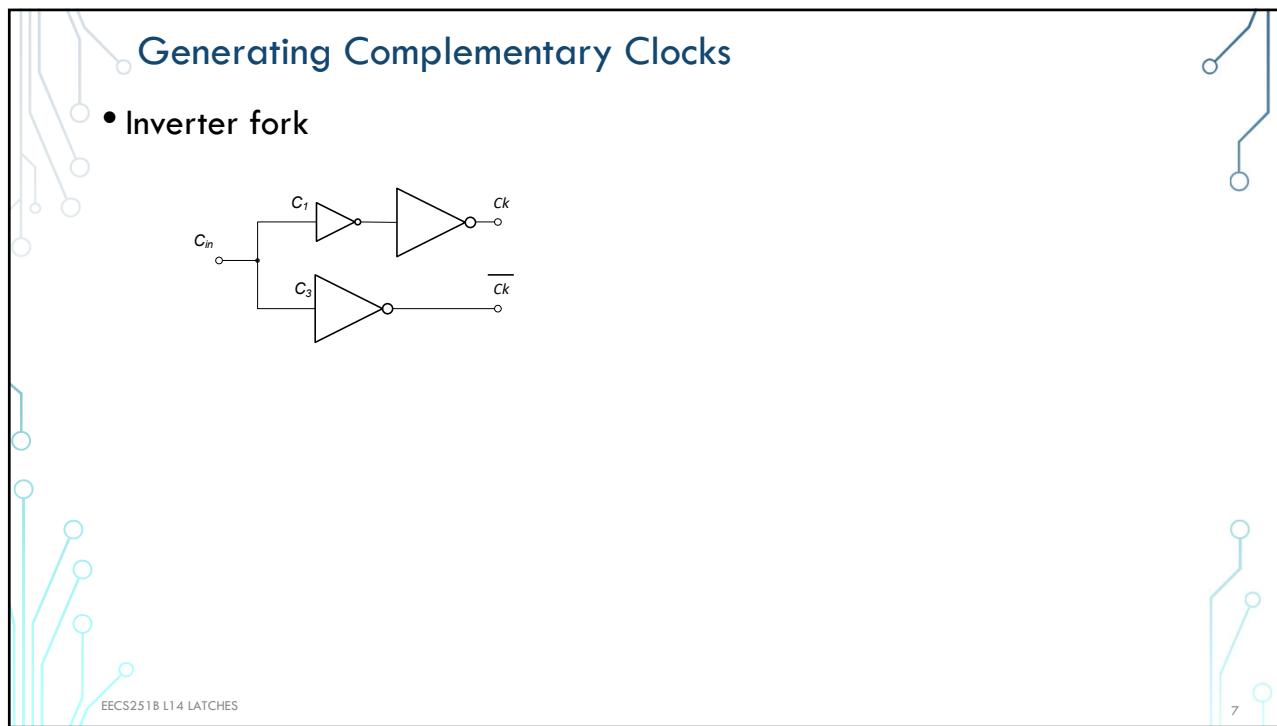
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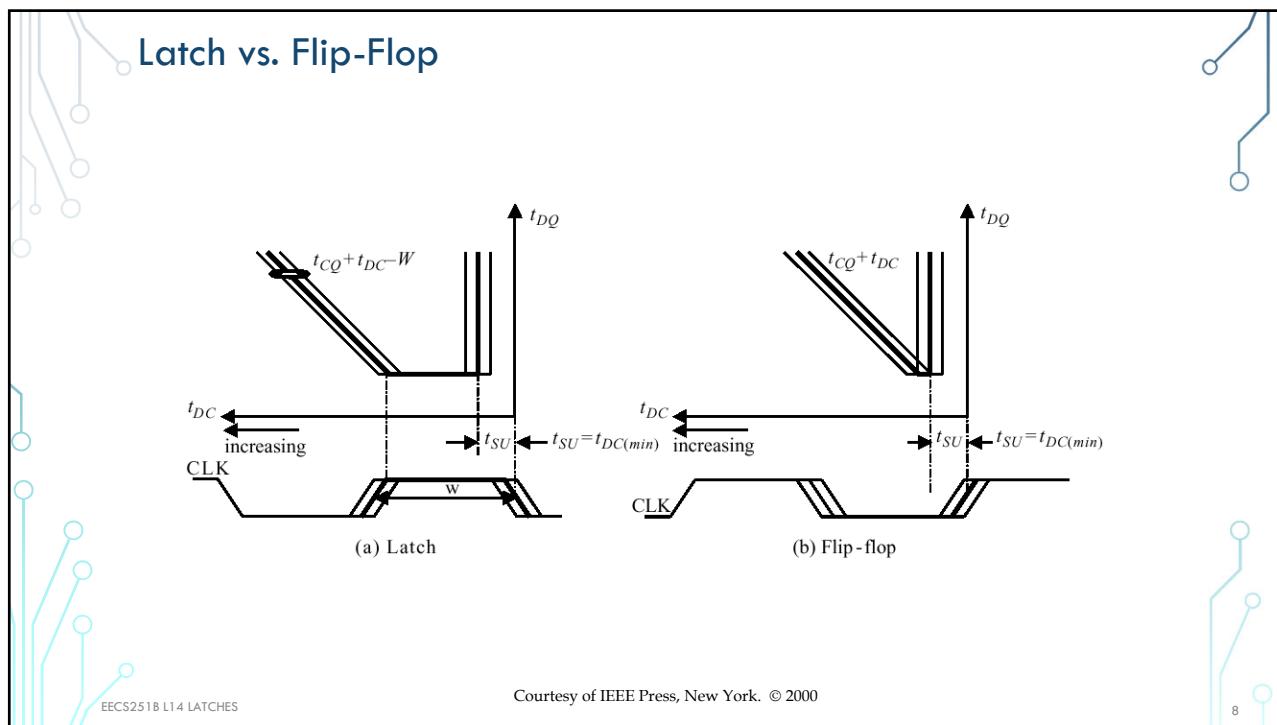
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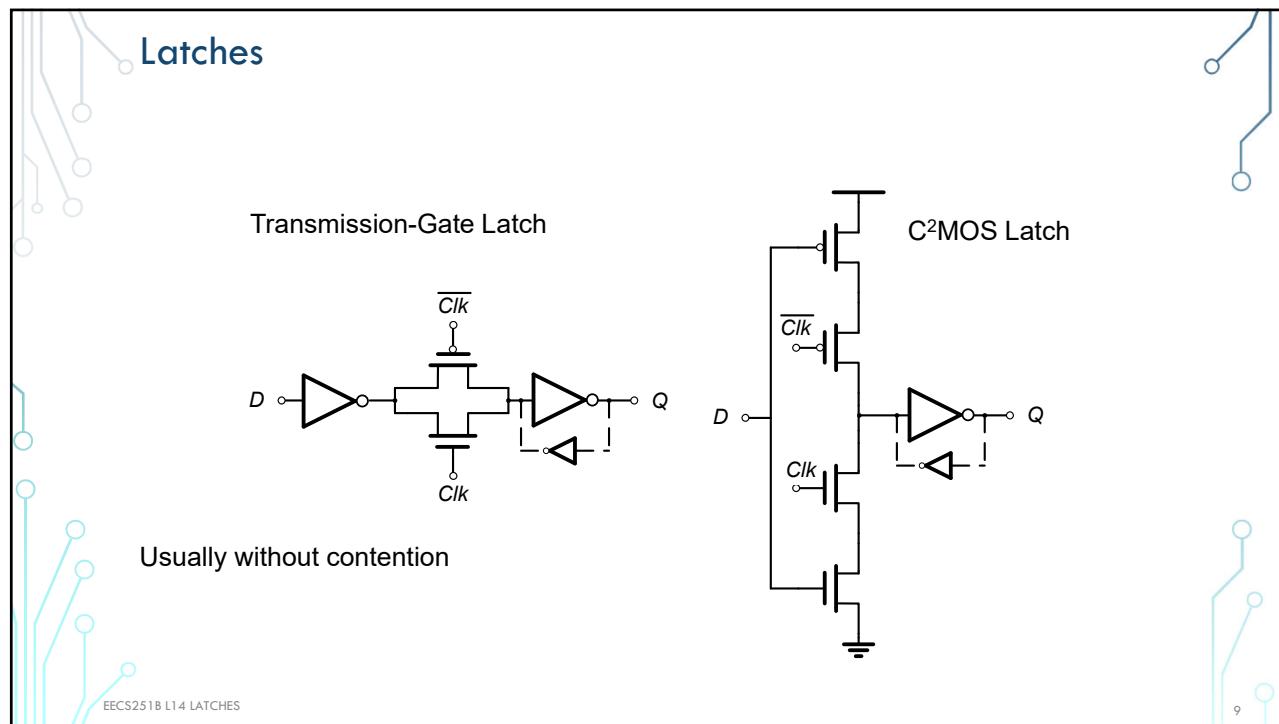
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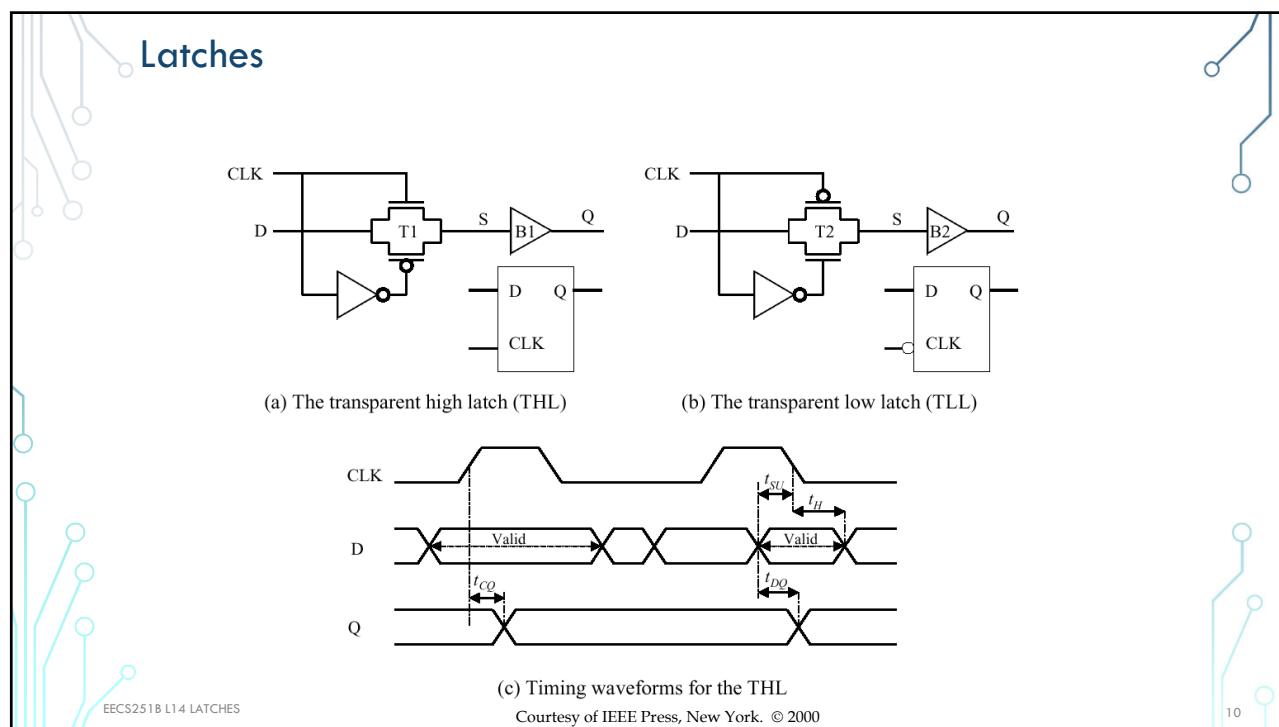
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Announcements

- Quiz 1 next Tuesday, in lecture
- Lab 5 due this week
- Midterm reports due next week
 - 4 pages, conference format

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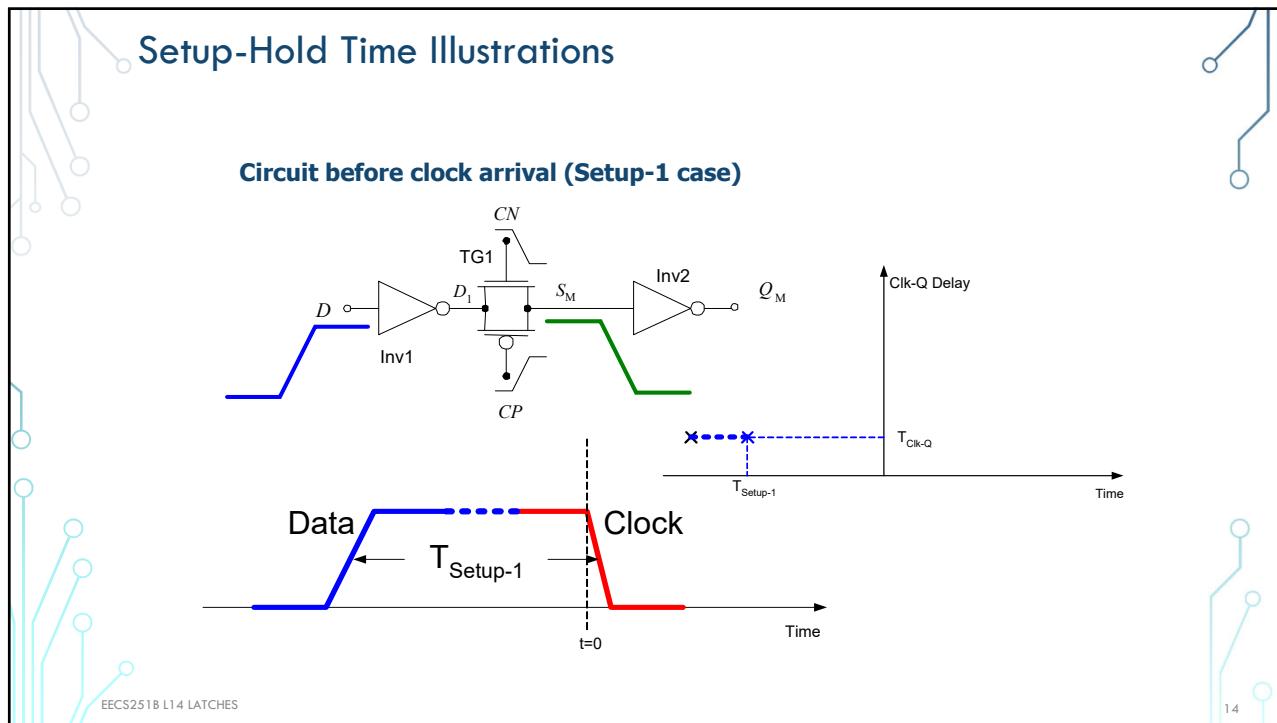
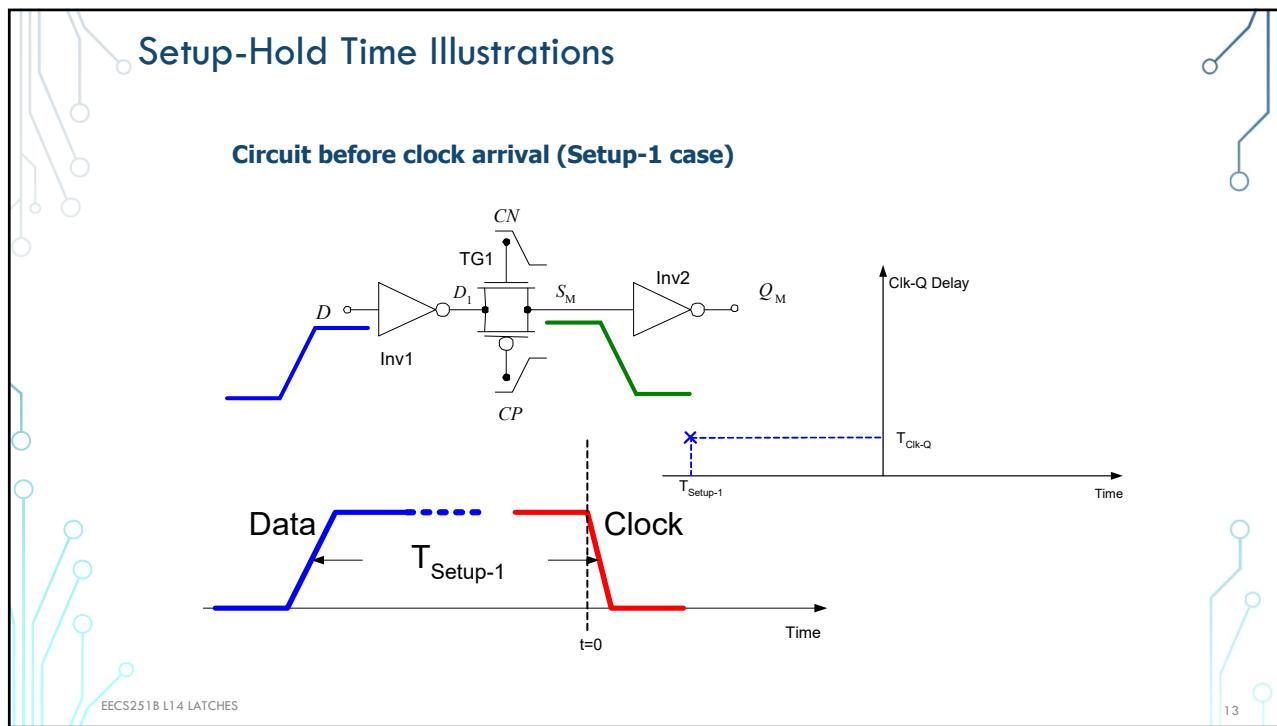


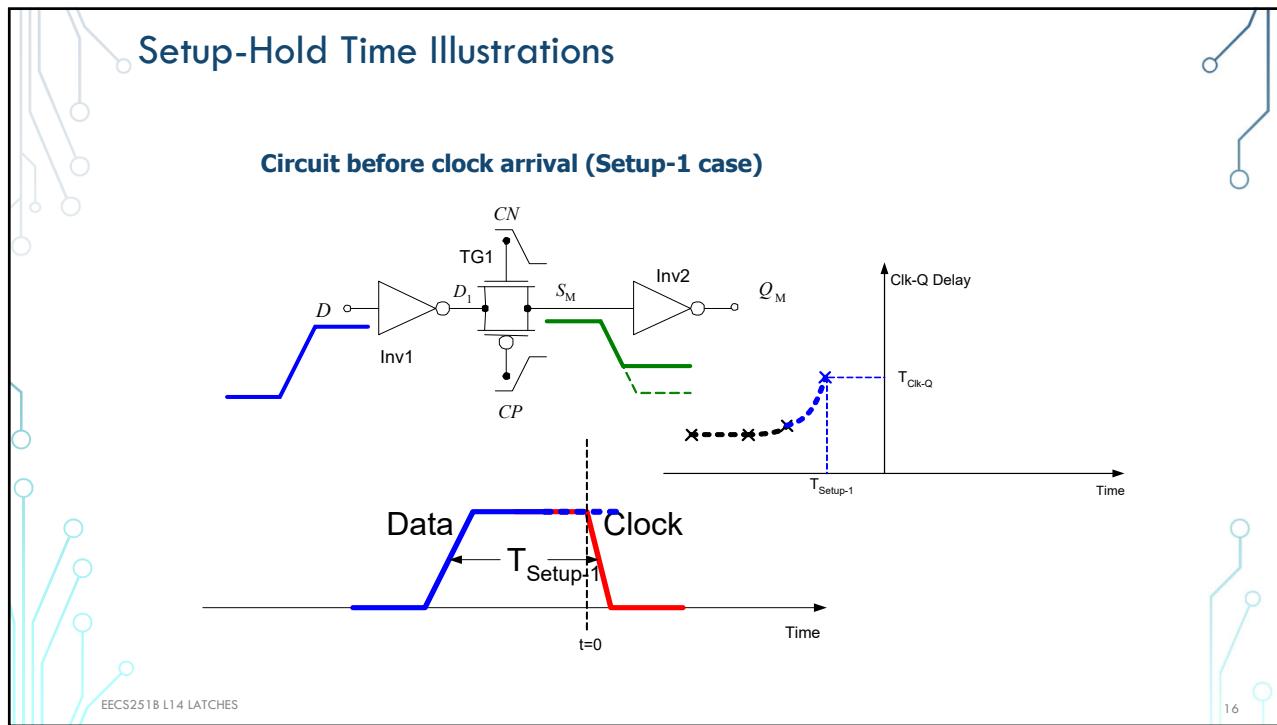
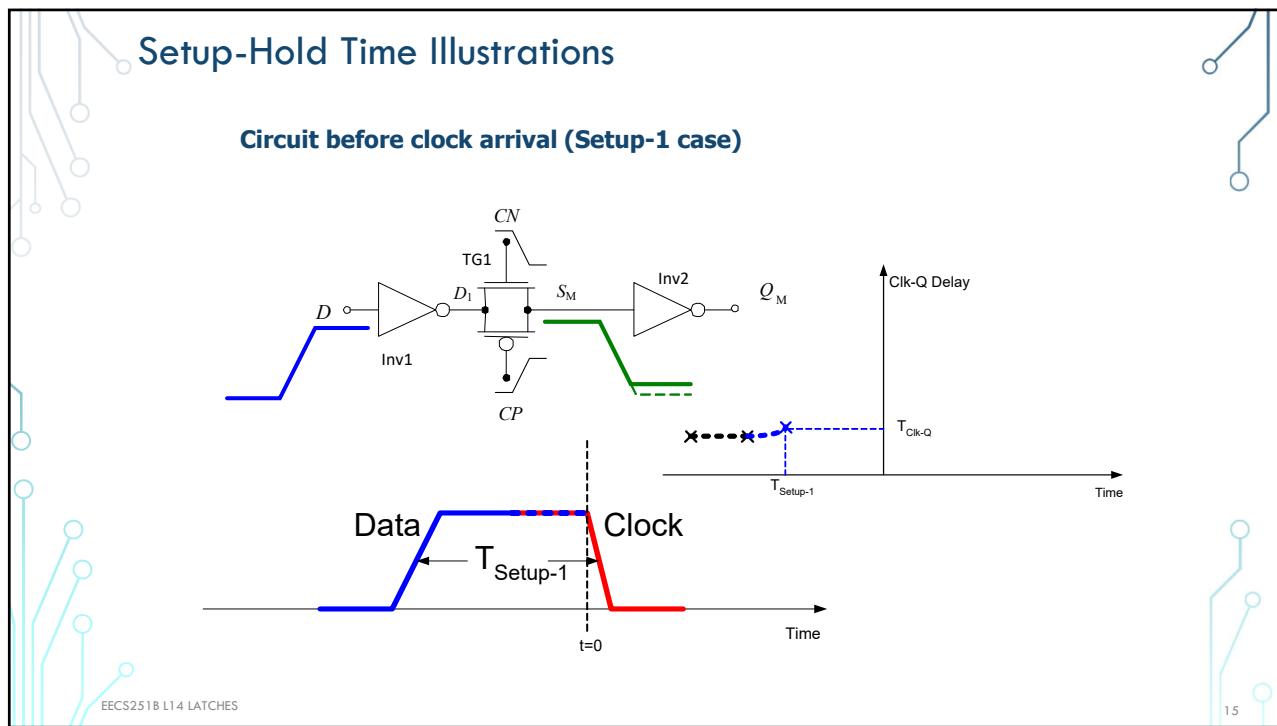
Design for Performance

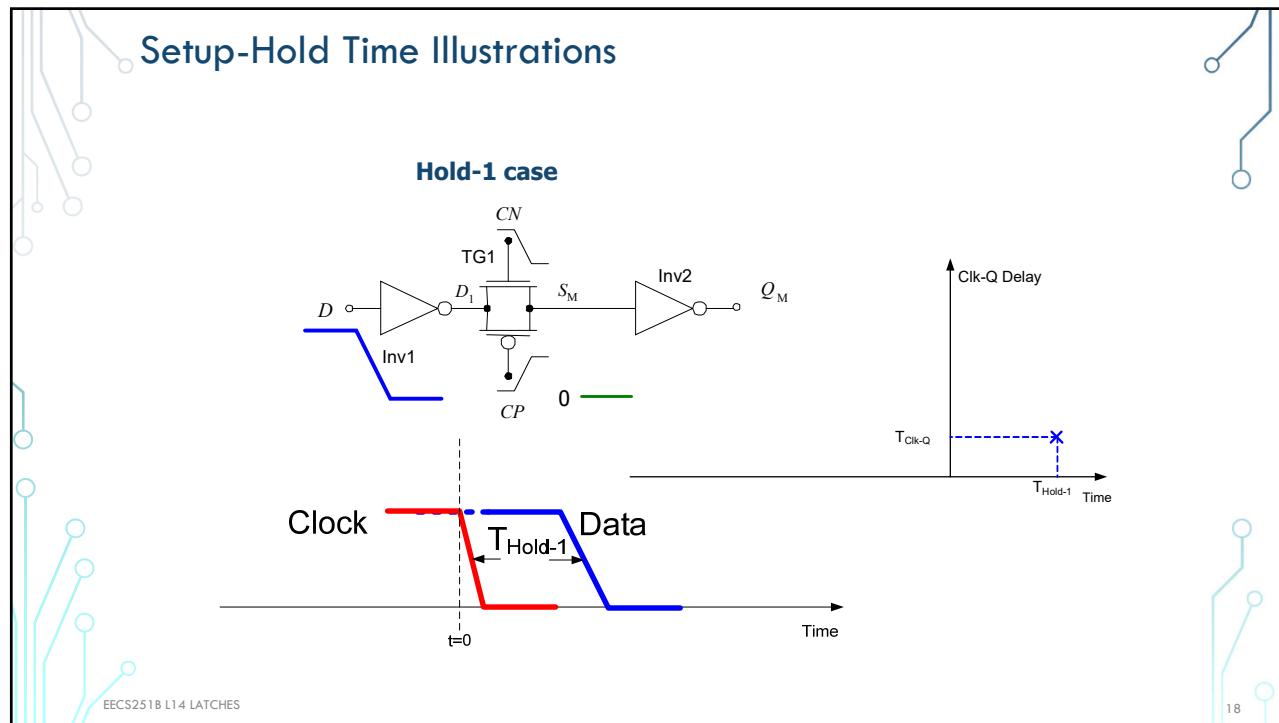
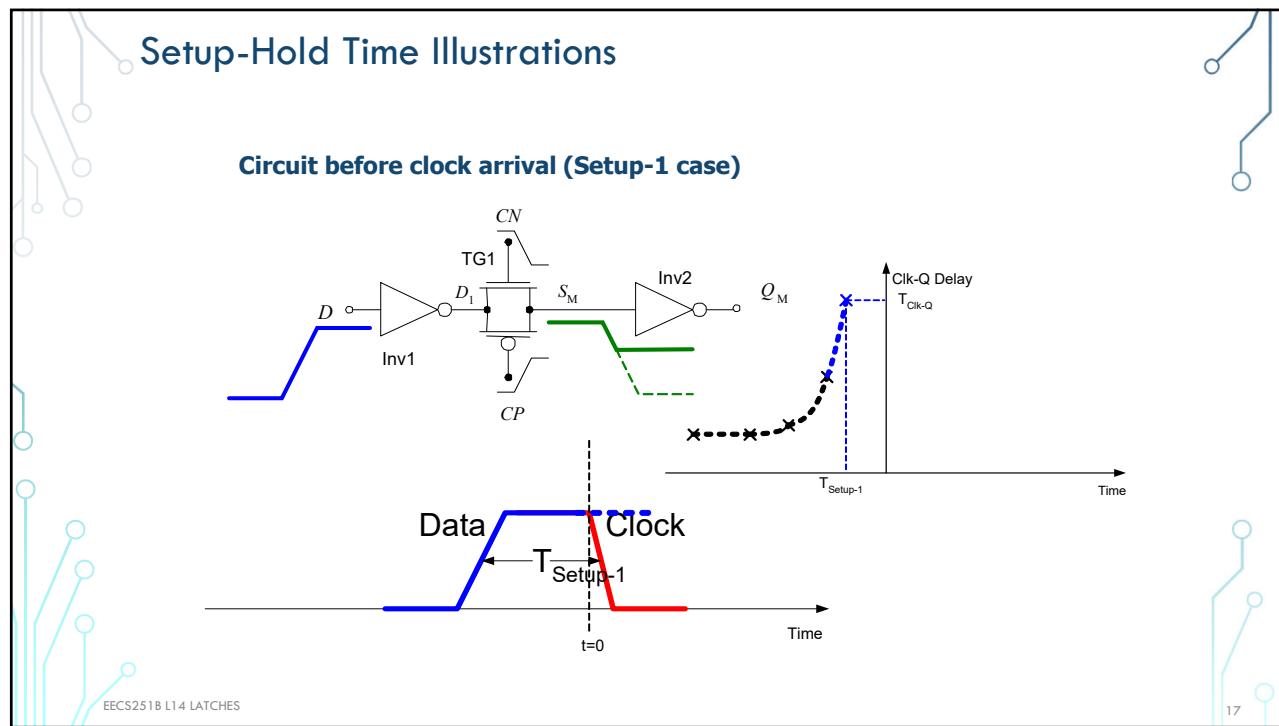
Delay, Setup, Hold

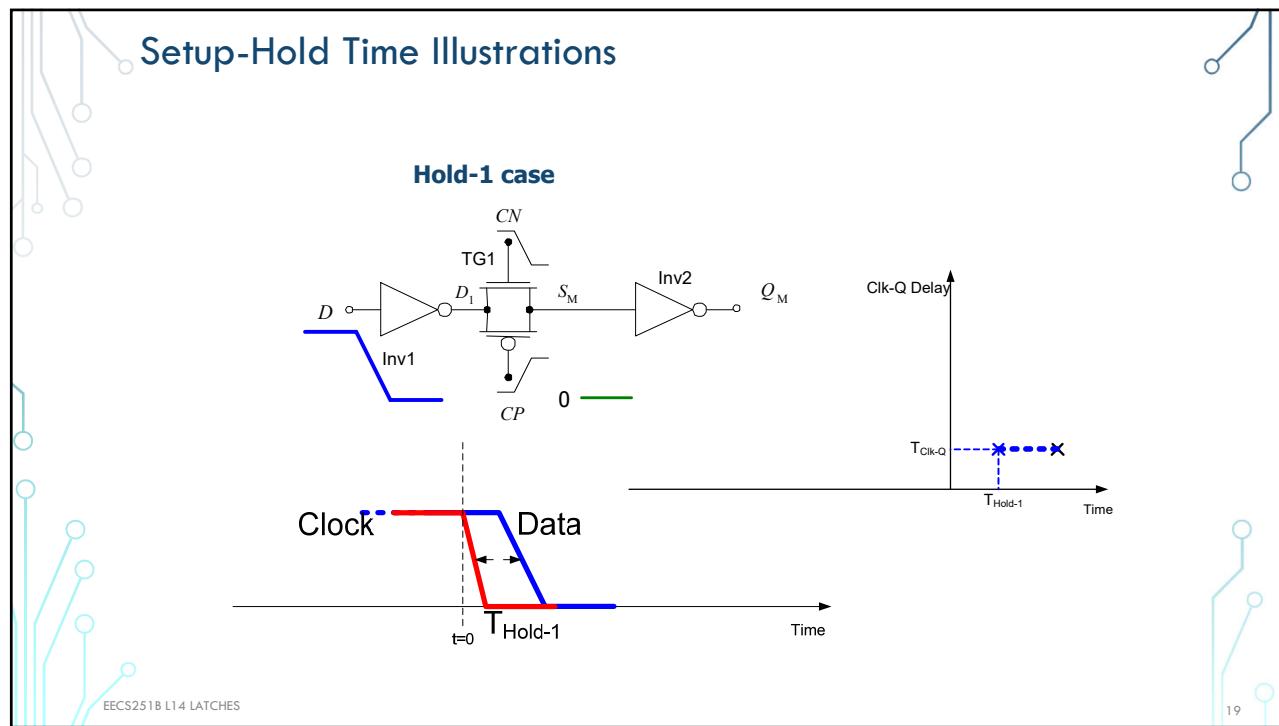
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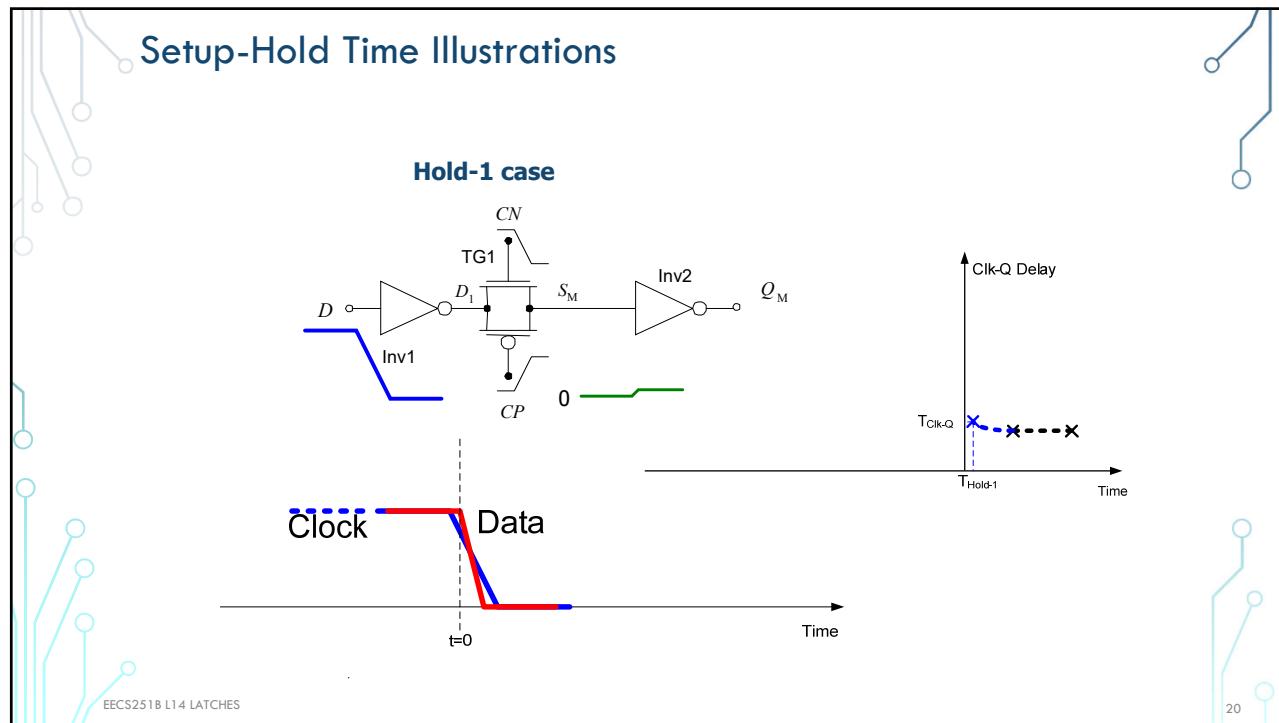




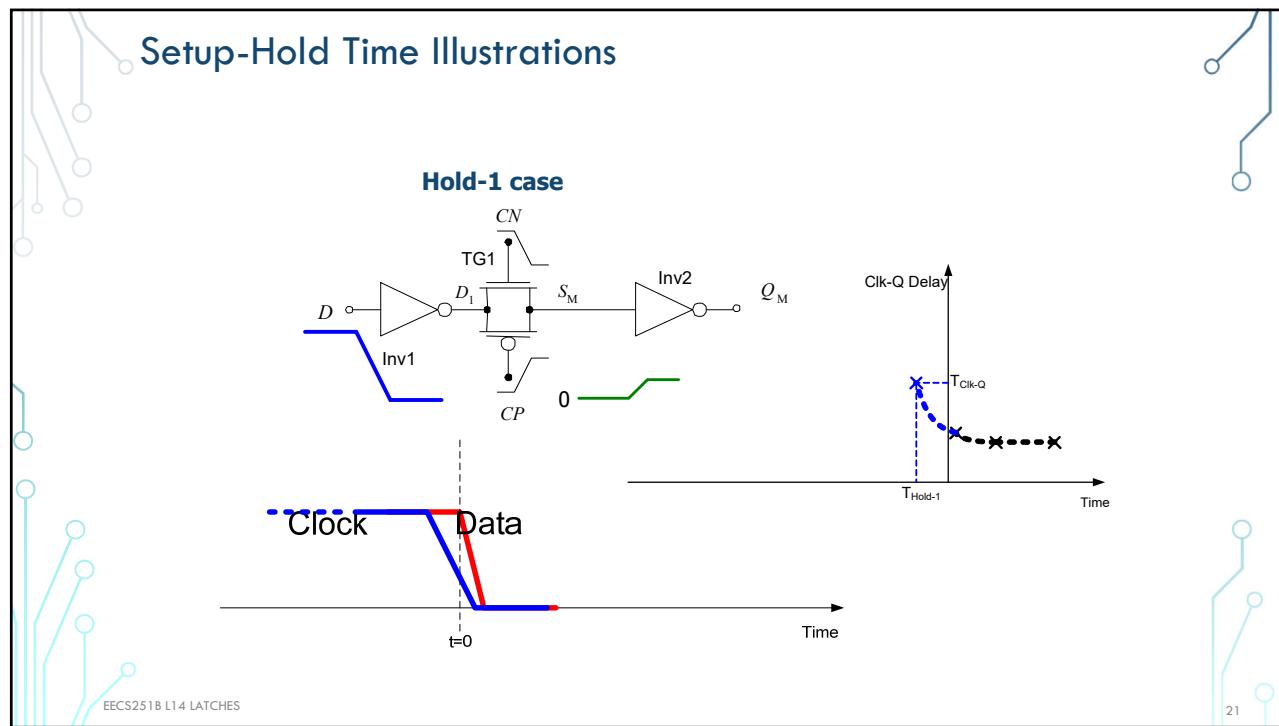




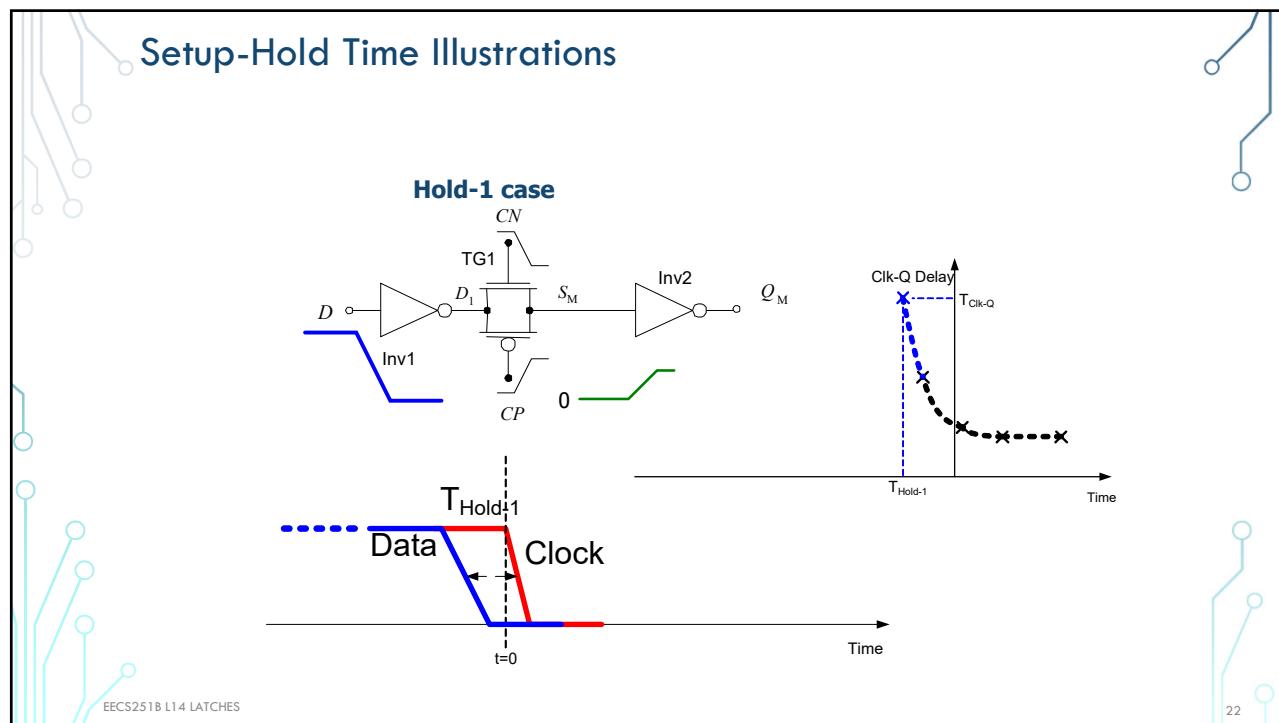
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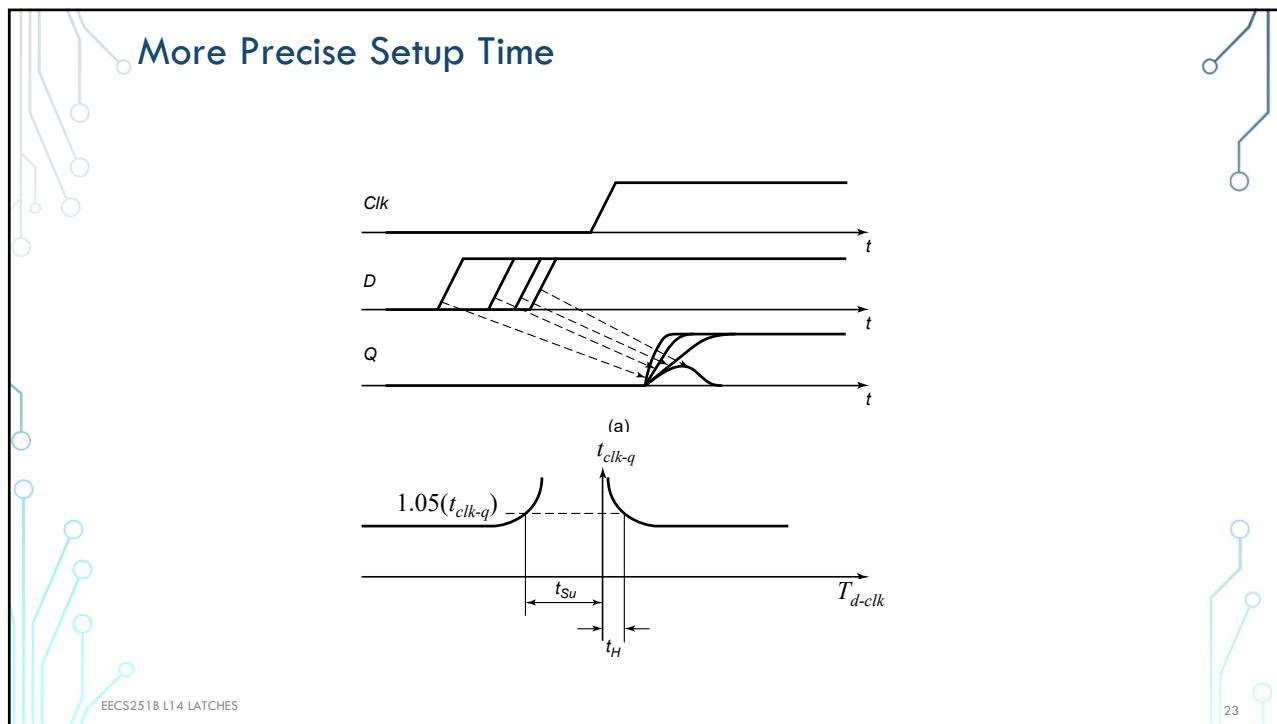
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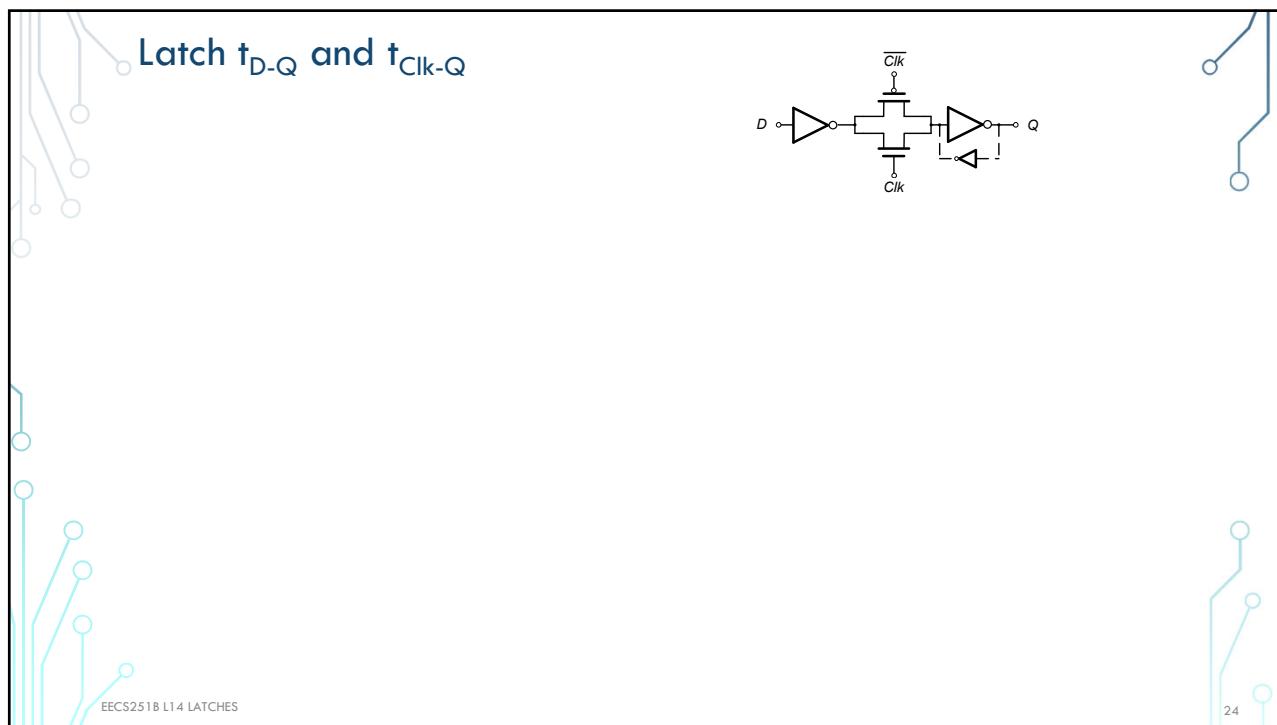
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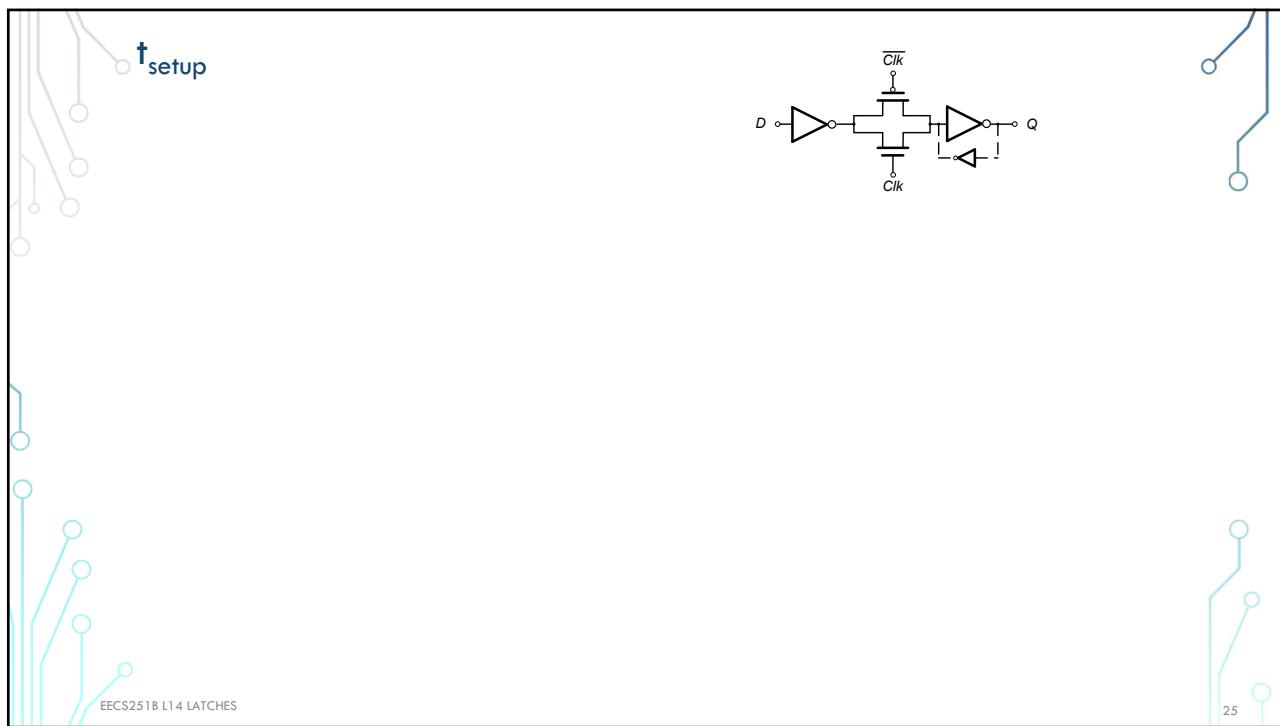
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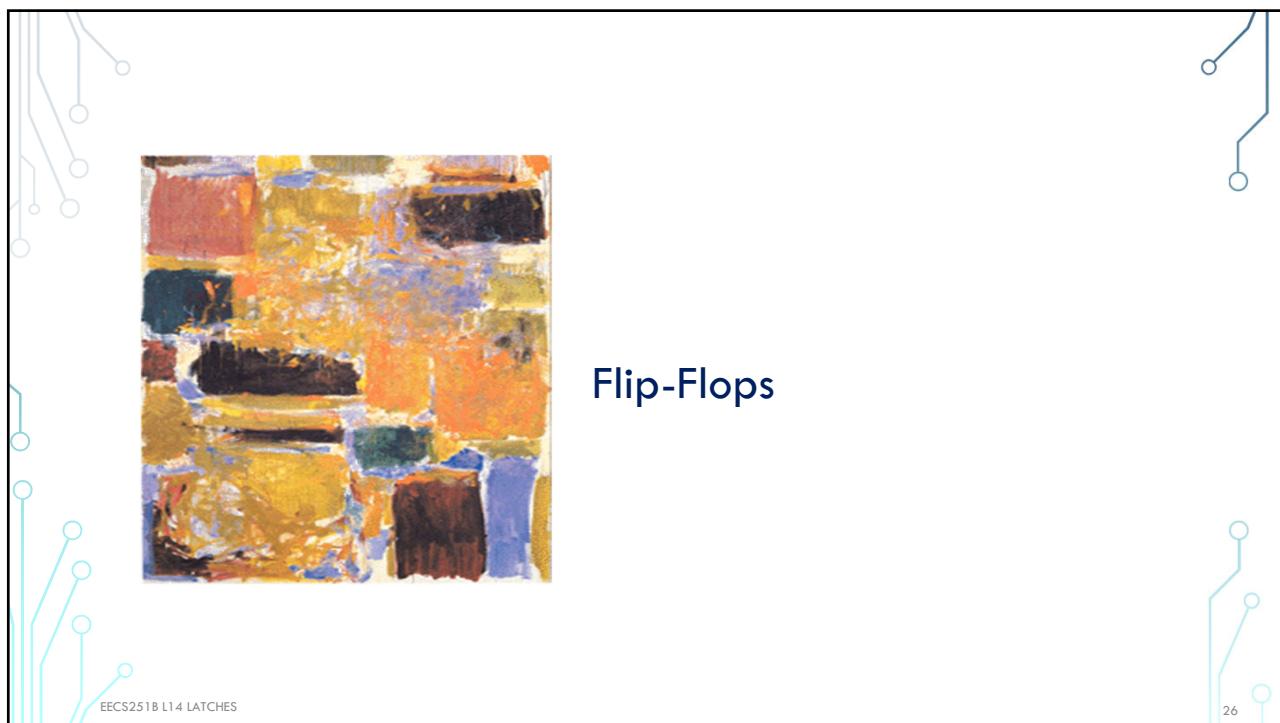
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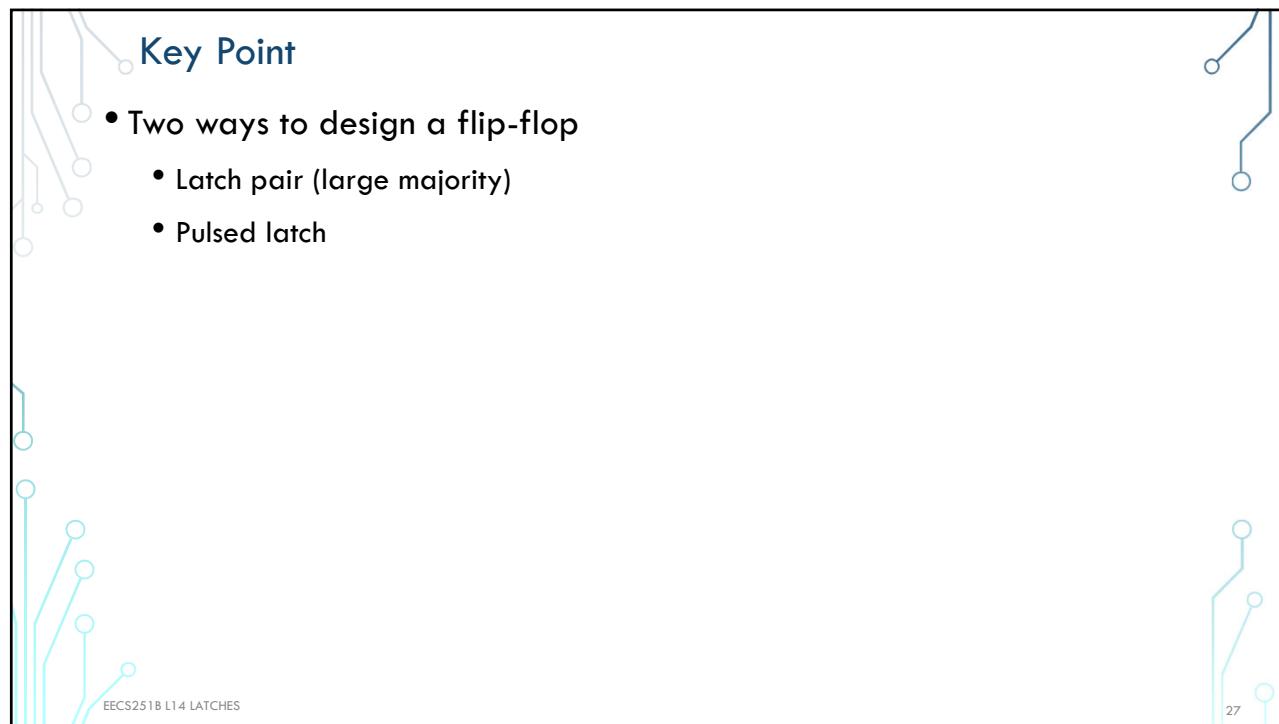


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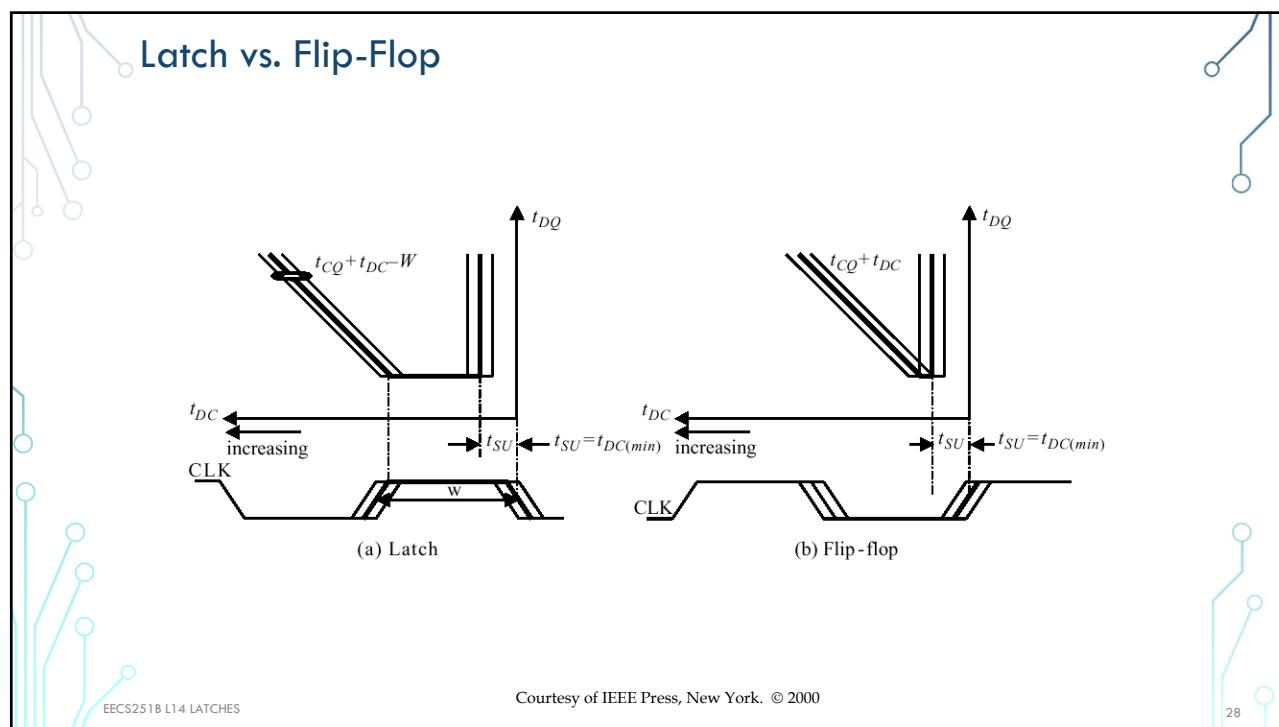


Flip-Flops

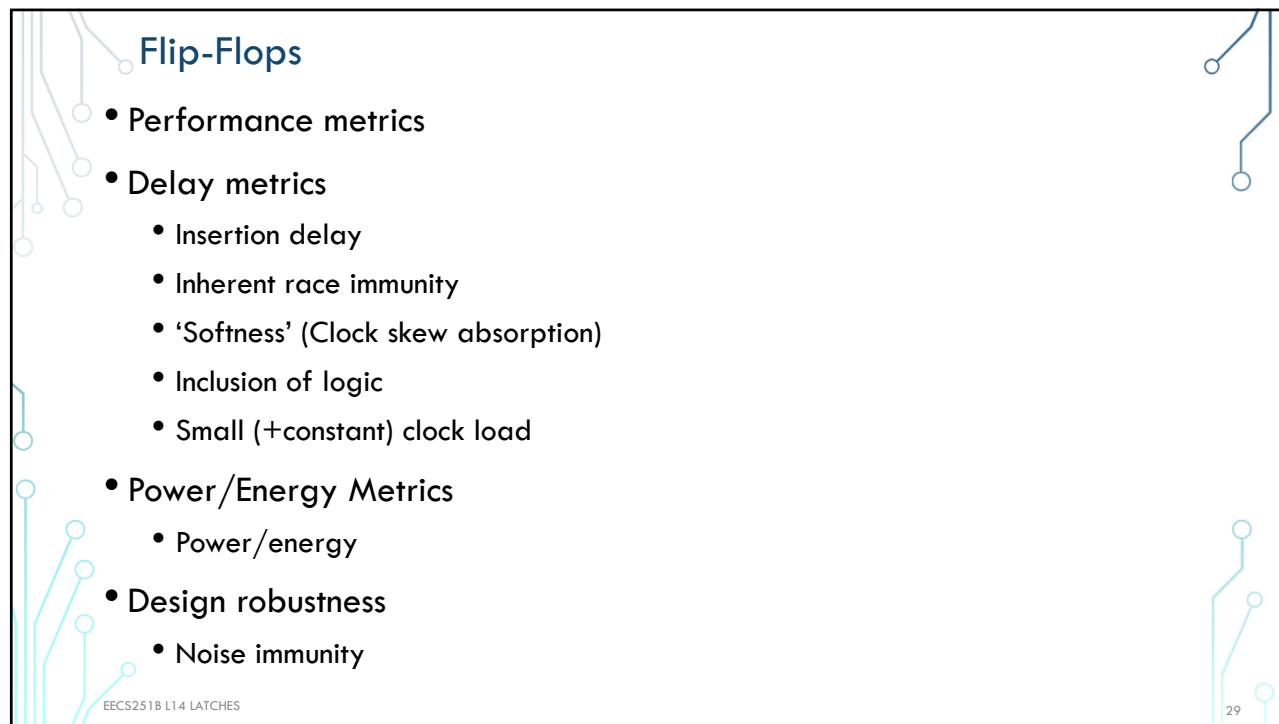
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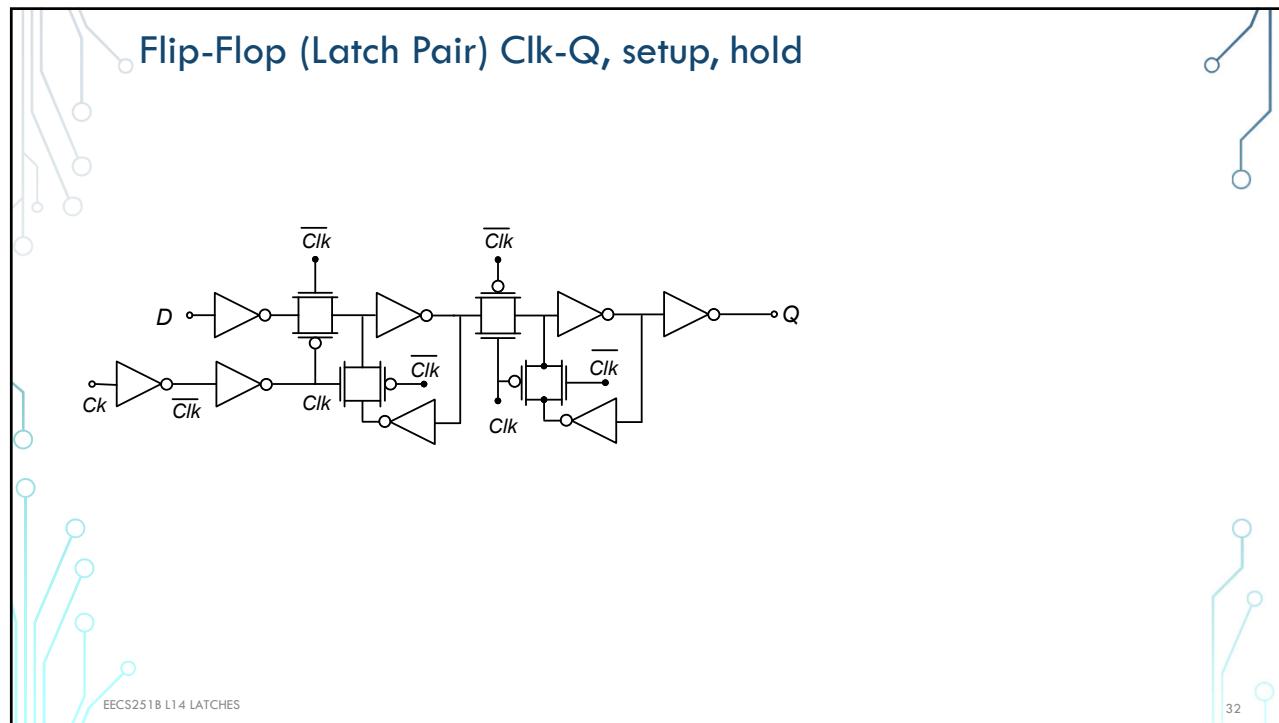
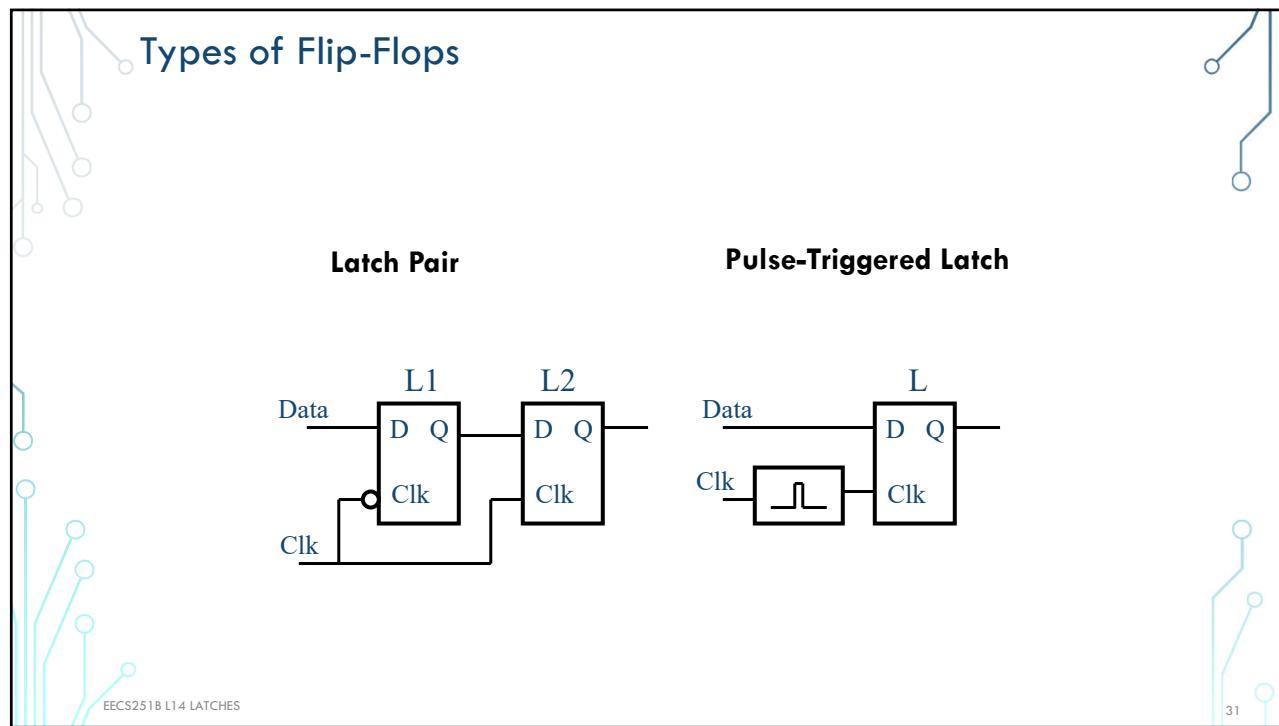
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Flip-Flop Timing Characterization

- Combinational logic delay is a function of output load and input slope
- Sequential timing (flip-flop):
 - t_{clk-q} is function of output load and clock rise time
 - $t_{S_{U/H}}$ are functions of D and Clk rise/fall times

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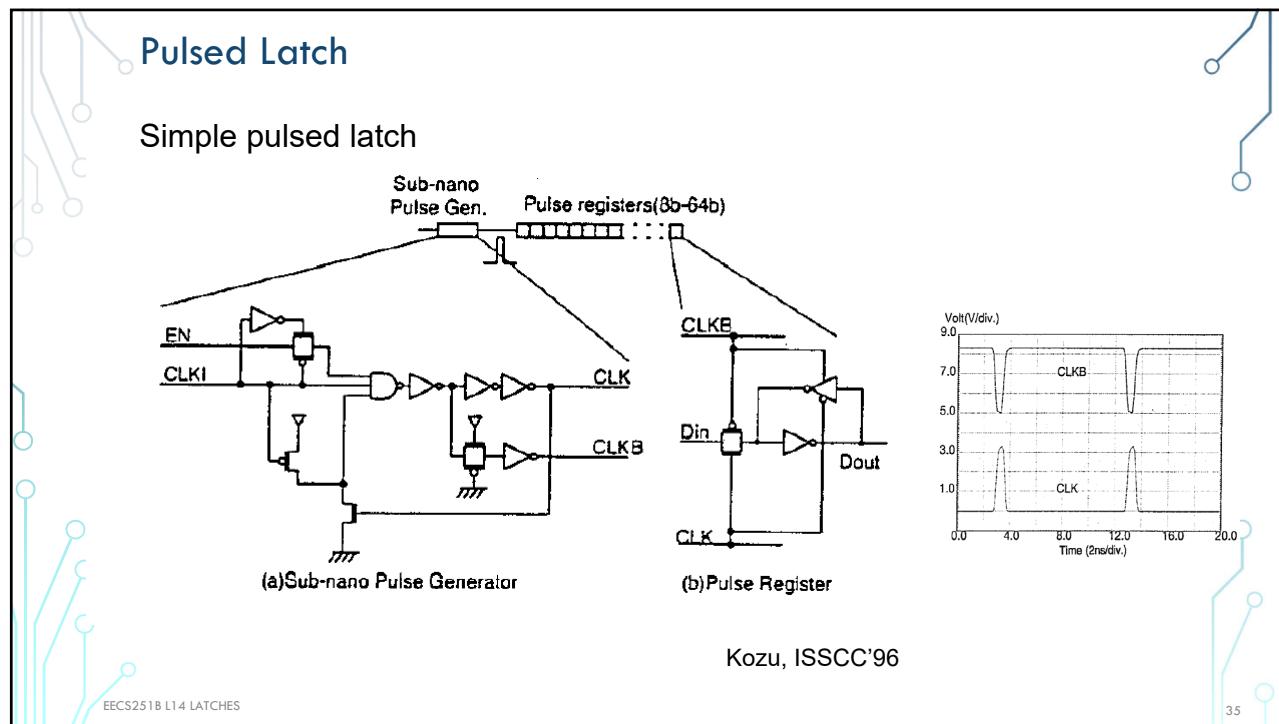
Pulse-Triggered Latches

- First stage is a pulse generator
 - generates a pulse (glitch) on a rising edge of the clock
- Second stage is a latch
 - captures the pulse generated in the first stage
- Pulse generation results in a negative setup time
- Frequently exhibit a soft edge property
- Note: power is always consumed in the pulse generator
 - Often shared by a group (register)

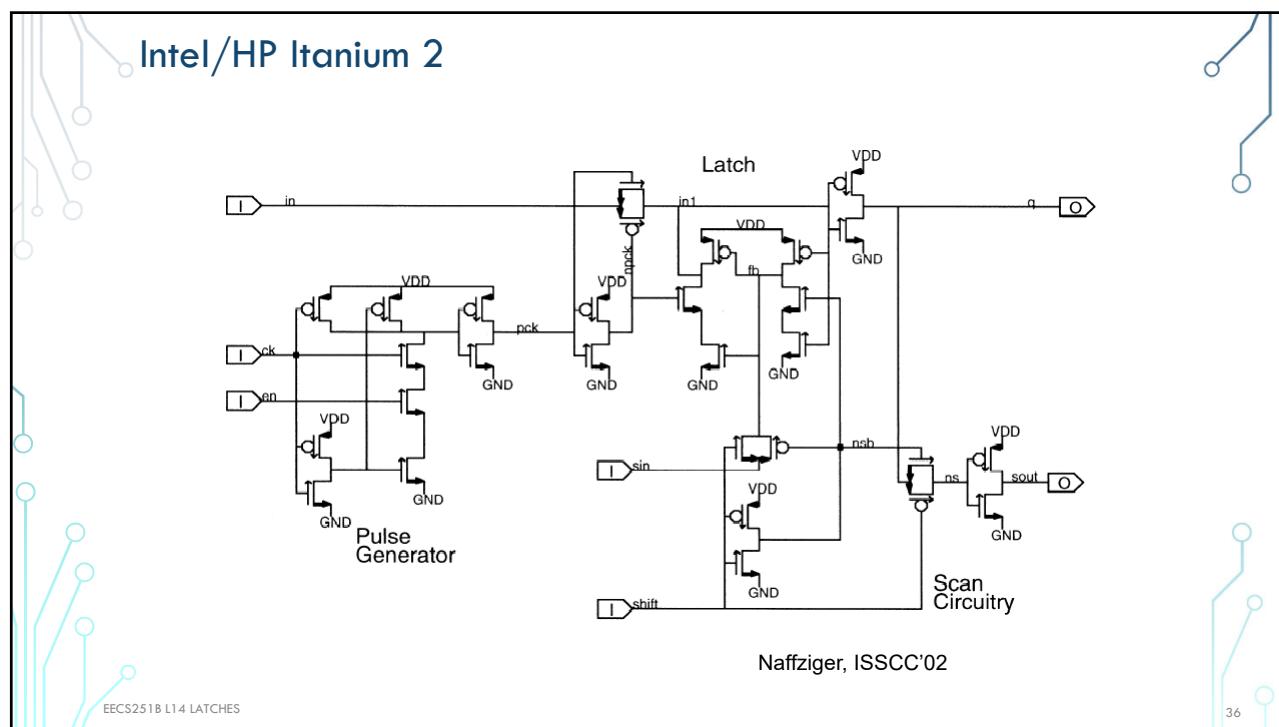
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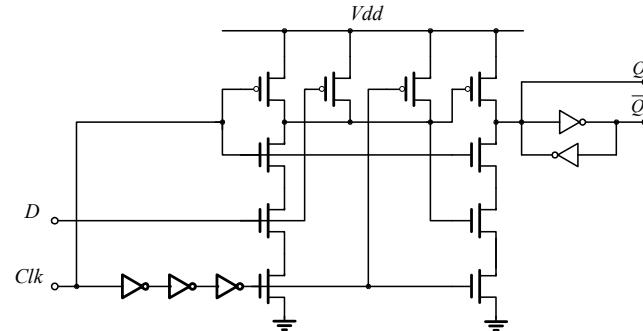
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Pulsed Latches

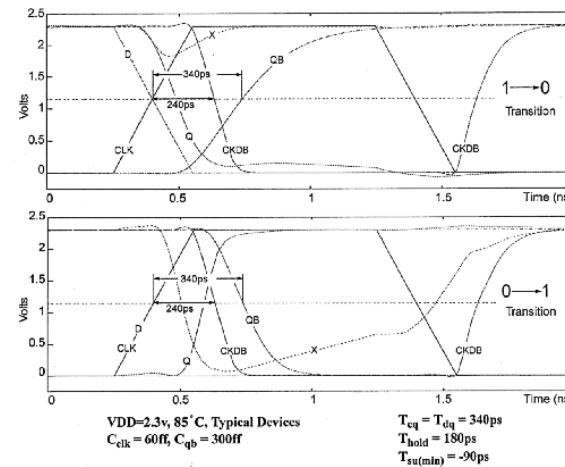
Hybrid Latch Flip-Flop, AMD K-6
Partovi, ISSCC'96



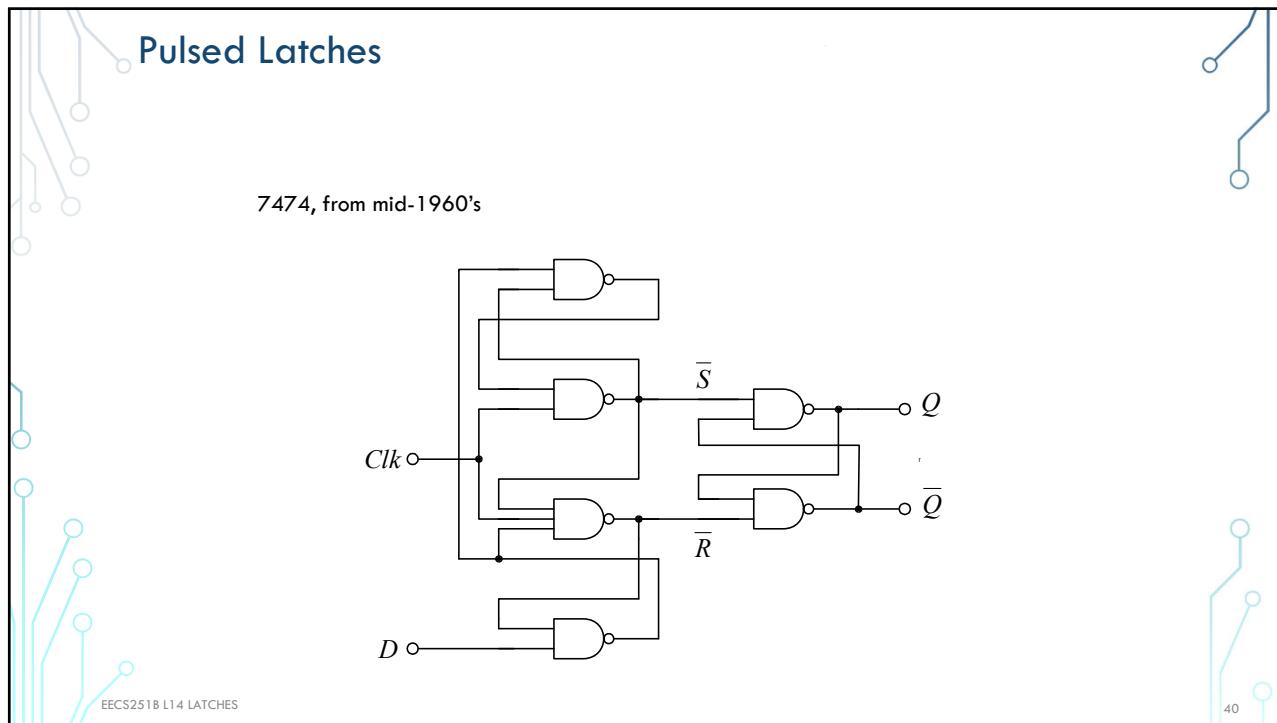
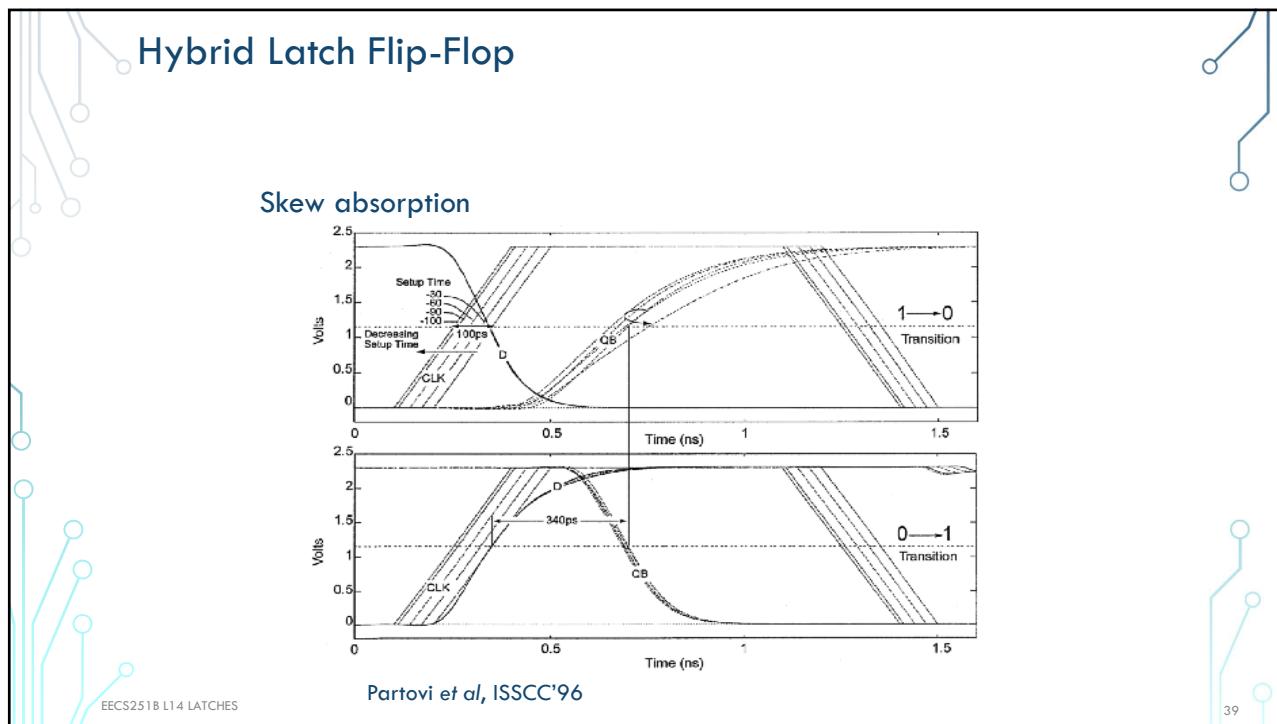
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HLFF Operation

1-0 and 0-1 transitions at the input with 0ps setup time



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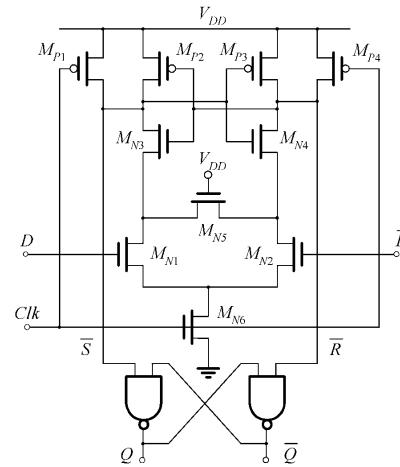


Pulsed Latches

Sense-amplifier-based flip-flop, Matsui 1992.
DEC Alpha 21264, StrongARM 110

First stage is a sense amplifier, precharged to high, when $C/k = 0$
After rising edge of the clock sense amplifier generates the pulse on S or R
The pulse is captured in S-R latch
Cross-coupled NAND has different propagation delays of rising and falling edges

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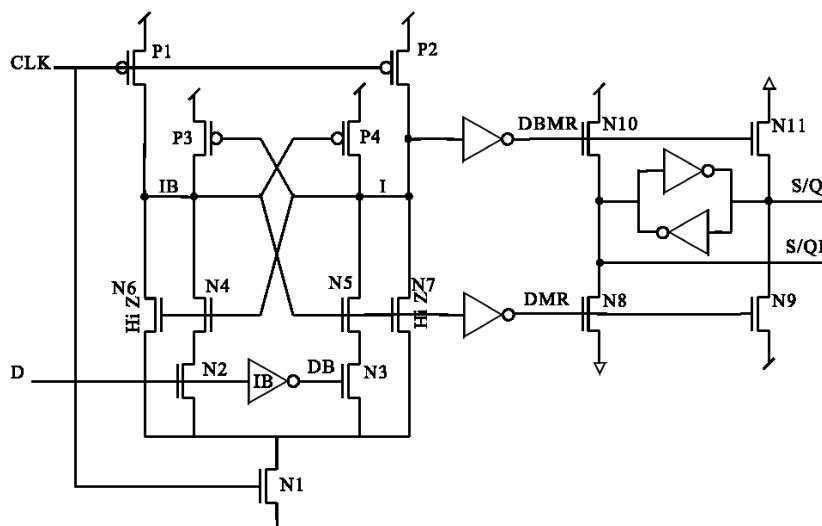


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Sense Amplifier-Based Flip-Flop

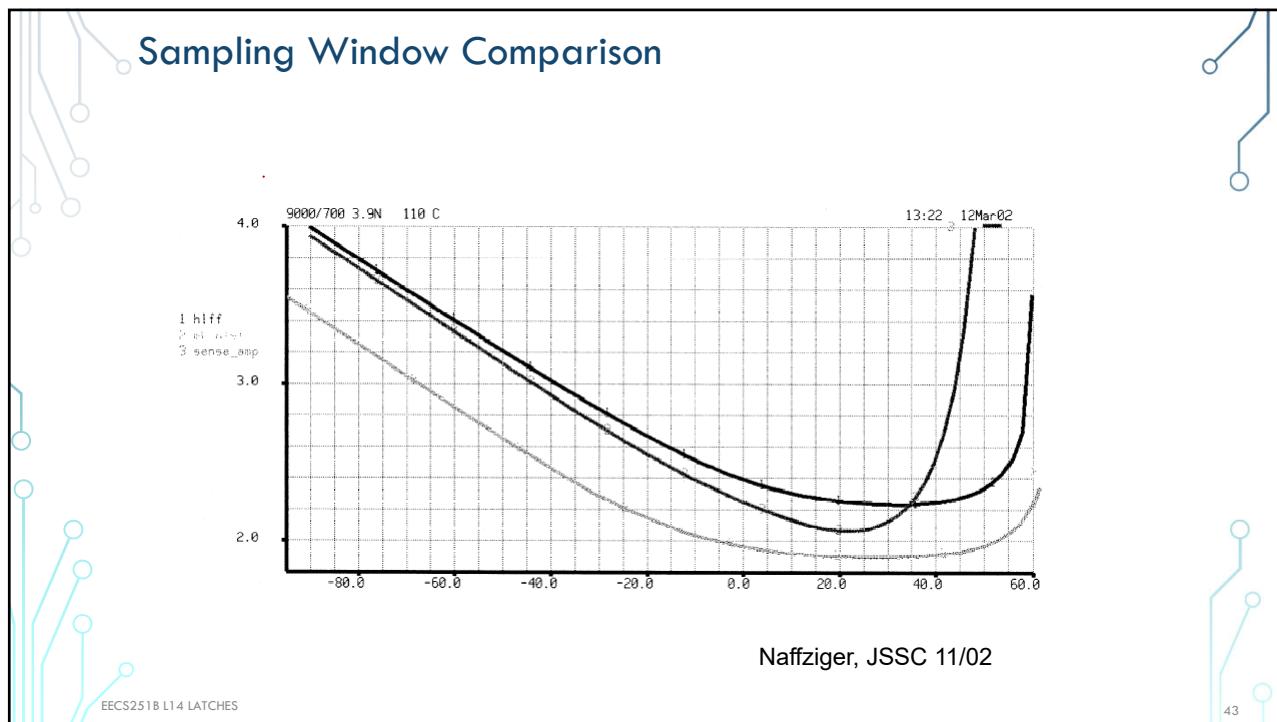
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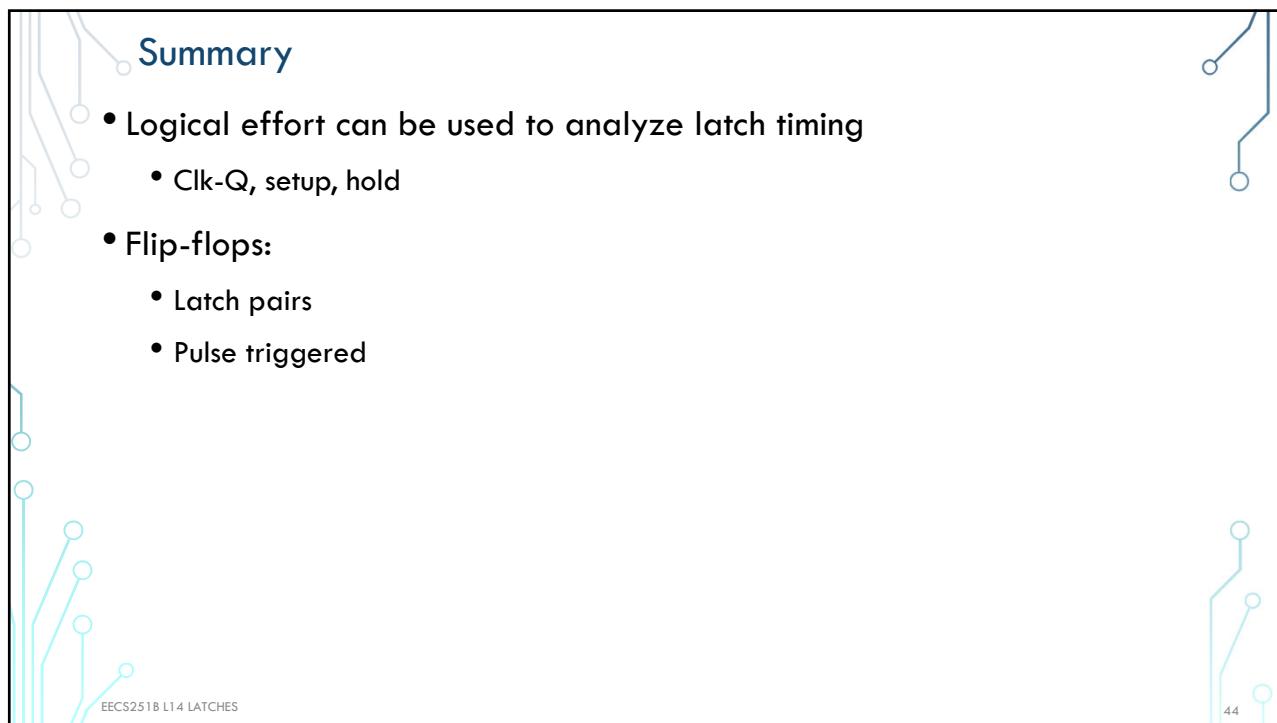


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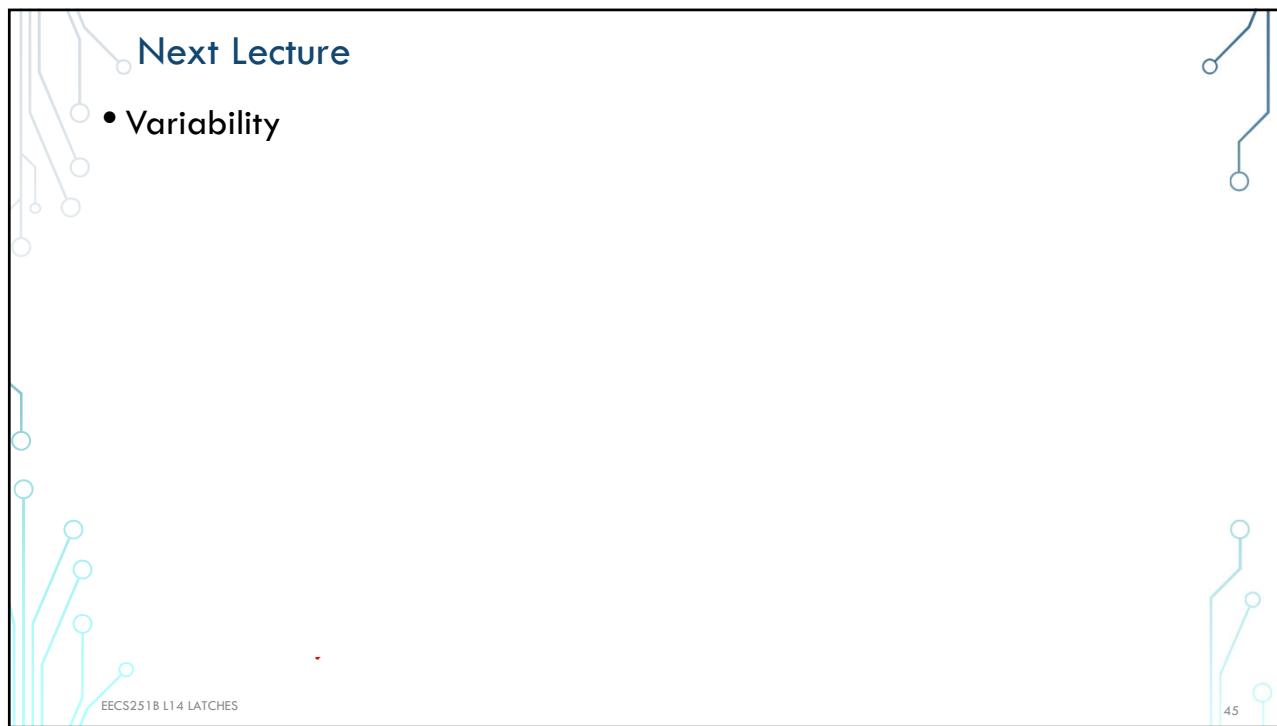
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